

Search Notes**Application/Control No.**

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Examiner

Nguyen N. Hanh

Applicant(s)/Patent under Reexamination

ISHIHARA ET AL.

Art Unit

2834

SEARCHED

Class	Subclass	Date	Examiner
310	261	10/17/2006	HN
310	216	10/17/2006	HN
310	217	10/17/2006	HN
310	218	10/17/2006	HN

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner